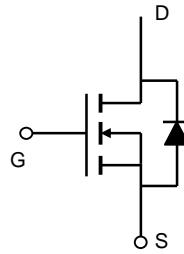


## 20V N-Channel MOSFET

### General Description

The FNK02N08E uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 0.5V while retaining a 12V  $V_{GS(MAX)}$  rating. This device is suitable for use as load switch and general purpose FET application.



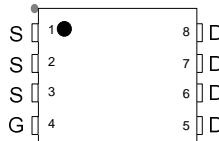
### Product Summary

$V_{DS}$  (V) = 20V

$I_D$  = 20A

$R_{DS(ON)} < 7.5\text{m}\Omega$  ( $V_{GS} = 4.5\text{V}$ )

$R_{DS(ON)} < 12\text{m}\Omega$  ( $V_{GS} = 2.5\text{V}$ )



Top View



Marking and pin Assignment

### Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
FNK02N08E	FNK02N08E	DFN3.3x3.3	Ø330mm	12mm	5000 units

### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current <sup>A</sup>	$I_D$	100	A
		92	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	400	
Power Dissipation <sup>A</sup>	$P_D$	3.1	W
		2	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	30	40	°C/W
		65	80	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	20	25	°C/W



**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=16\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			10	$\mu\text{A}$
					25	
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 10\text{V}$			10	$\mu\text{A}$
$\text{BV}_{\text{GSO}}$	Gate-Source Breakdown Voltage	$V_{DS}=0\text{V}, I_G=\pm 250\mu\text{A}$	$\pm 12$			V
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.45	0.7	1	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	100			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=15\text{A}$ $T_J=125^\circ\text{C}$		4.3	7.5	$\text{m}\Omega$
				7.8	12	
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=12\text{A}$		37		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.73	1	V
$I_S$	Maximum Body-Diode Continuous Current				4.8	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$		1810		pF
$C_{\text{oss}}$	Output Capacitance			232		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			200		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.6		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=12\text{A}$		17.9		nC
$Q_{\text{gs}}$	Gate Source Charge			1.5		nC
$Q_{\text{gd}}$	Gate Drain Charge			4.7		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=10\text{V}, R_L=1.0\Omega, R_{\text{GEN}}=3\Omega$		2.5		ns
$t_r$	Turn-On Rise Time			7.2		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			49		ns
$t_f$	Turn-Off Fall Time			10.8		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=12\text{A}, dI/dt=100\text{A}/\mu\text{s}$		20.2		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=12\text{A}, dI/dt=100\text{A}/\mu\text{s}$		8		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

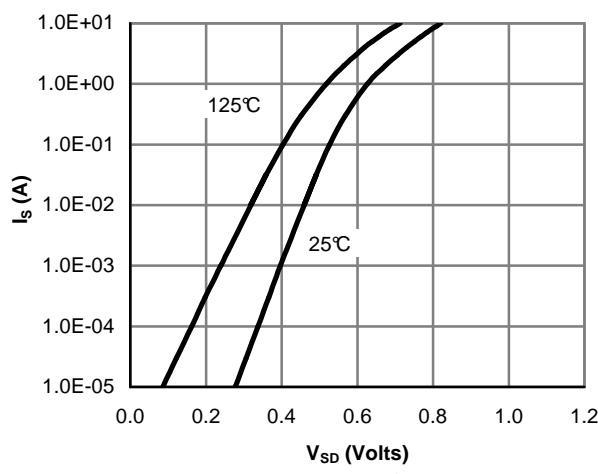
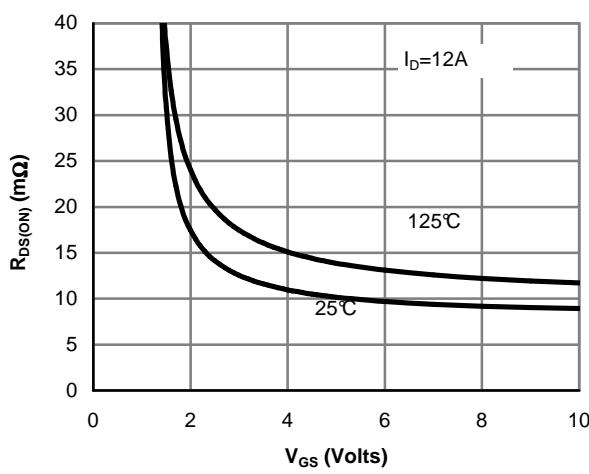
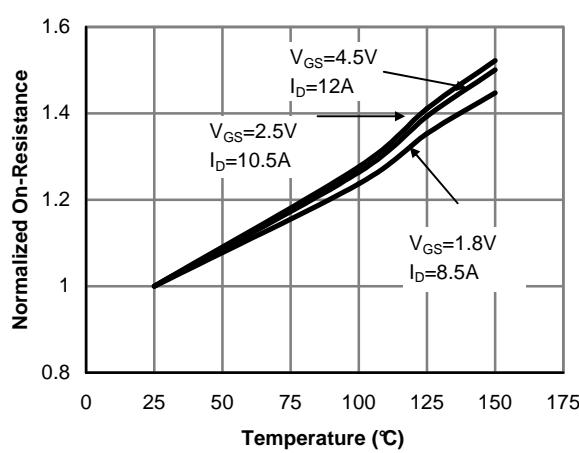
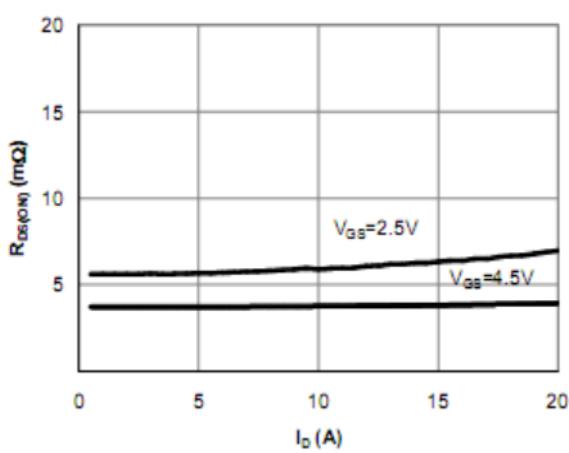
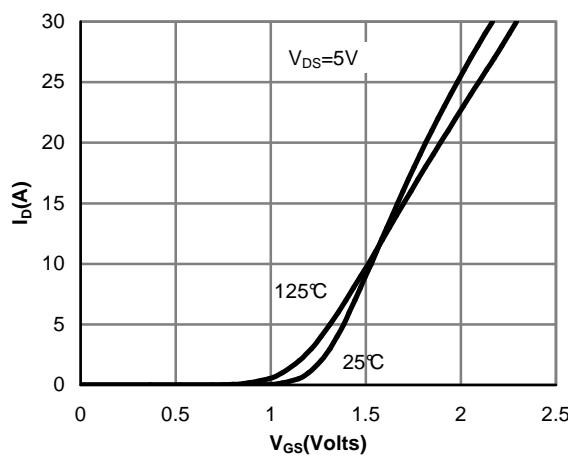
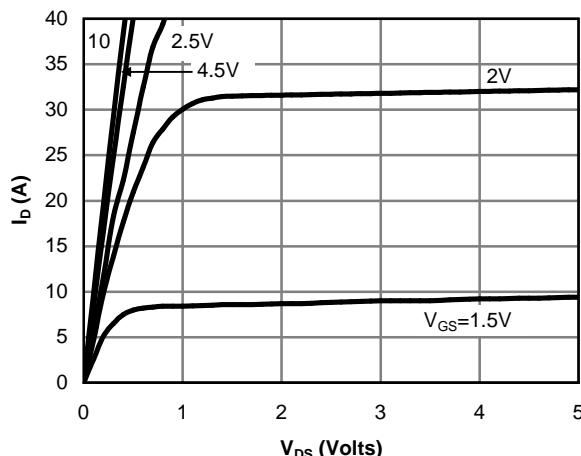
C: The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using 300  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

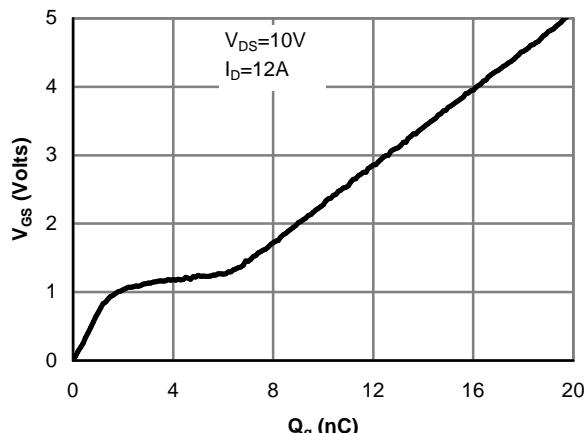


Figure 7: Gate-Charge Characteristics

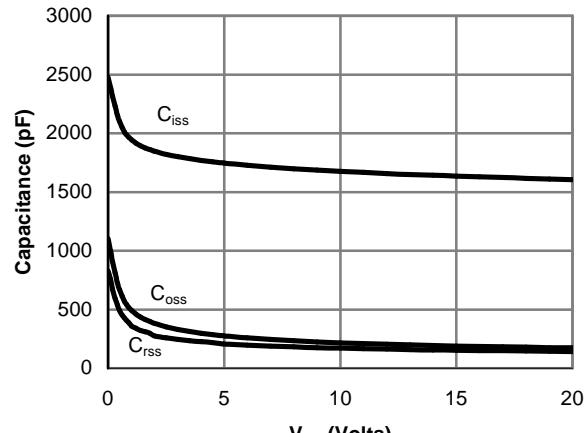


Figure 8: Capacitance Characteristics

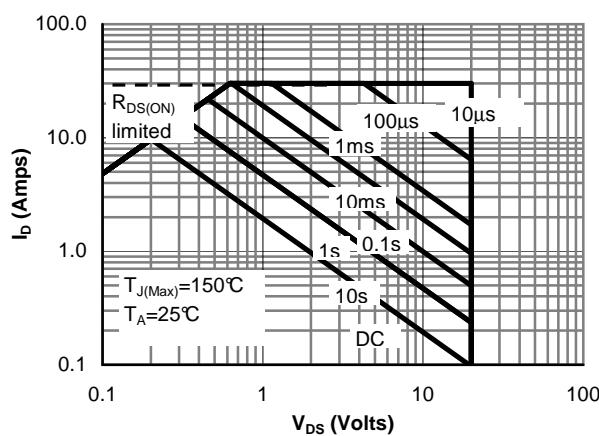


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

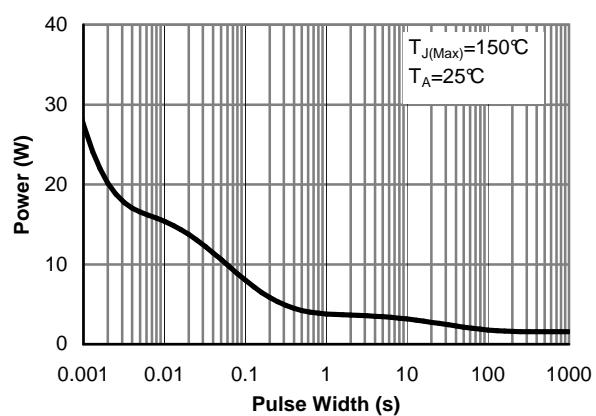


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

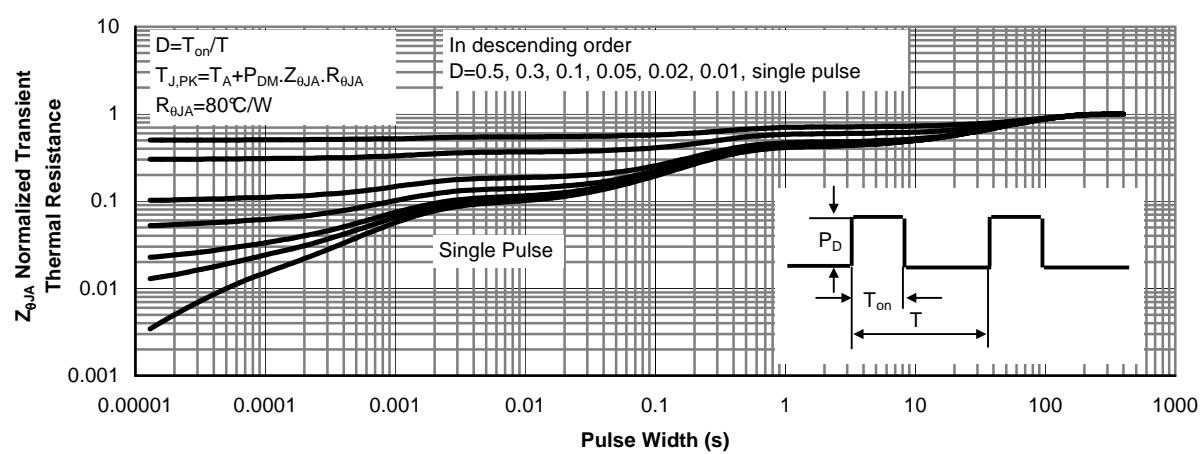
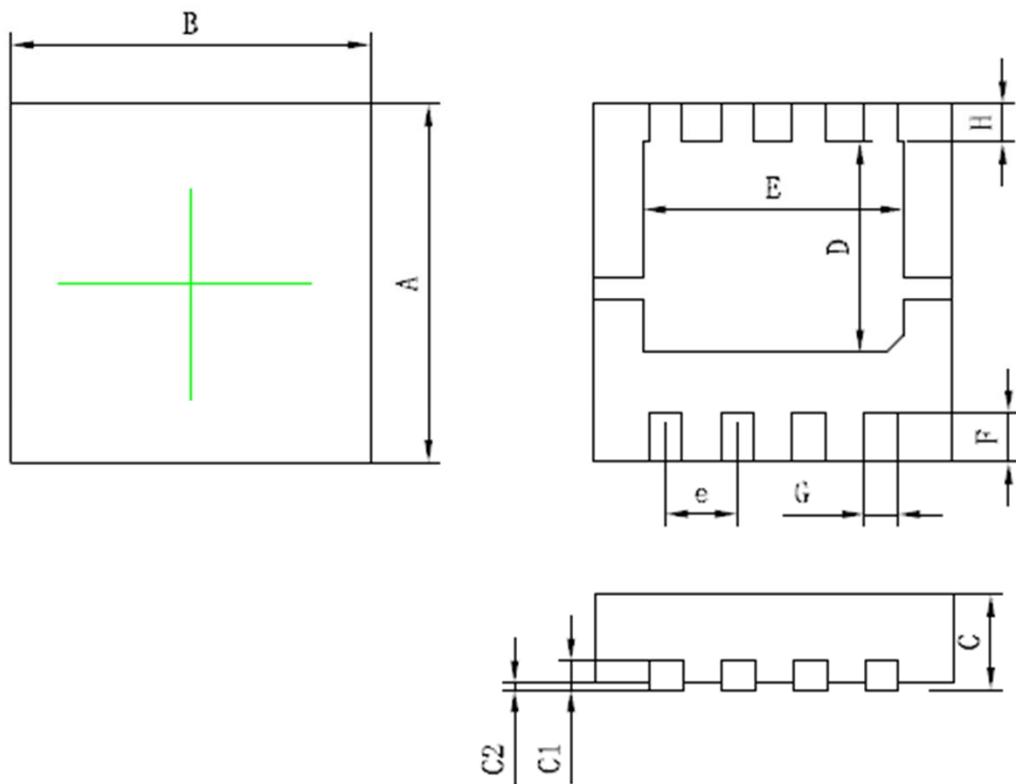


Figure 11: Normalized Maximum Transient Thermal Impedance

## DFN3333 Package Information



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	3.15	3.25	3.35
B	3.15	3.25	3.35
C	0.75	0.80	0.85
C1	0.18	0.20	0.22
C2			0.05
D	1.80	1.90	2.00
E	2.20	2.35	2.50
F	0.40	0.45	0.50
G	0.25	0.30	0.35
H	0.30	0.35	0.40
e	0.65 BSC		

单位: mm

**Disclaimer:**

- FNK reserves the right to make changes to the information herein for the improvement of the design and performance without further notice! Customers should obtain the latest relevant information before placing orders and should verify that such information is complete and current.
- All semiconductor products malfunction or fail with some probability under special conditions. When using FNK products in system design or complete machine manufacturing, it is the responsibility of the buyer to comply with the safety standards strictly and take essential measures to avoid situations in which a malfunction or failure of such Silan products could cause loss of body injury or damage to property.
- FNK will supply the best possible product for customers!